

# PMV30UN

μTrenchMOS<sup>TM</sup> ultra low level FET Rev. 01 — 25 June 2003

**Product data** 

# **Product profile**

# 1.1 Description

N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS™ technology.

Product availability:

PMV30UN in SOT23.

### 1.2 Features

Surface mount package

Fast switching.

### 1.3 Applications

Battery management

High-speed switches.

#### 1.4 Quick reference data

 $V_{DS} \le 20 \text{ V}$ 

 $P_{tot} \le 1.9 \text{ W}$ 

I<sub>D</sub> ≤ 5.7 A

R<sub>DSon</sub>  $\leq$  36 m $\Omega$ 

# **Pinning information**

Table 1: Pinning - SOT23 simplified outline and symbol

Pin	Description	Simplified outline		Symbol
1	gate (g)			_
2	source (s)		3	ď
3	drain (d)	1	2	g
		Top v	iew MSB003	
			SOT23	







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# 3. Limiting values

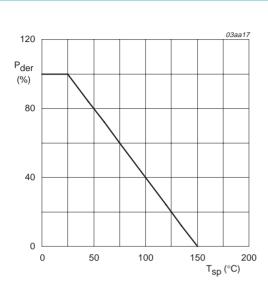
#### Table 2: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit	
$V_{DS}$	drain-source voltage (DC)	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	20	V	
$V_{DGR}$	drain-gate voltage (DC)	$25~^{\circ}\text{C} \le \text{T}_{\text{j}} \le 150~^{\circ}\text{C}; \text{R}_{\text{GS}} = 20~\text{k}\Omega$	-	20	V	
$V_{GS}$	gate-source voltage (DC)		-	±8	V	
I <sub>D</sub>	drain current (DC)	$T_{sp}$ = 25 °C; $V_{GS}$ = 4.5 V; Figure 2 and 3	-	5.7	Α	
		$T_{sp} = 100  ^{\circ}\text{C};  V_{GS} = 4.5  \text{V};  \text{Figure 2}$	-	3.65	Α	
I <sub>DM</sub>	peak drain current	$T_{sp}$ = 25 °C; pulsed; $t_p \le 10 \mu s$ ; Figure 3	-	23.1	Α	
P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C; Figure 1	-	1.9	W	
T <sub>stg</sub>	storage temperature		<b>-55</b>	+150	°C	
T <sub>j</sub>	junction temperature		<b>-55</b>	+150	°C	
Source-drain diode						
Is	source (diode forward) current (DC)	T <sub>sp</sub> = 25 °C	-	1.6	Α	
I <sub>SM</sub>	peak source (diode forward) current	$T_{sp}$ = 25 °C; pulsed; $t_p \le 10 \ \mu s$	-	6.4	Α	

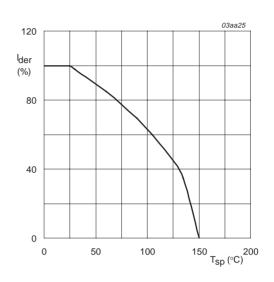
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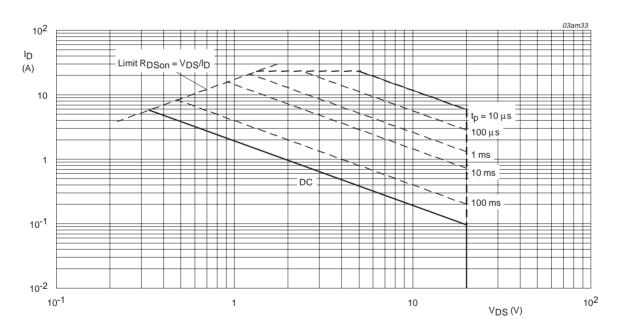
$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized total power dissipation as a function of solder point temperature.



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of solder point temperature.



 $T_{sp}$  = 25 °C;  $I_{DM}$  is single pulse;  $V_{GS}$  = 4.5 V

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.



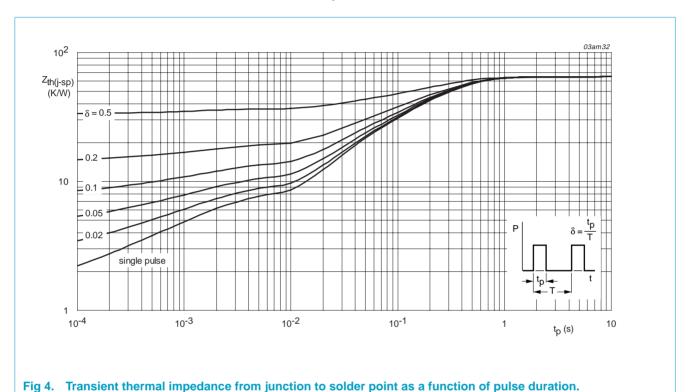
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# 4. Thermal characteristics

#### **Table 3: Thermal characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	Figure 4	-	-	65	K/W

# 4.1 Transient thermal impedance



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# 5. Characteristics

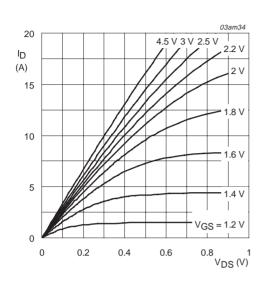
Table 4: Characteristics

 $T_i = 25 \,^{\circ}C$  unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V$				
		T <sub>j</sub> = 25 °C	20	-	-	V
		$T_j = -55 ^{\circ}\text{C}$	18	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; Figure 9				
		T <sub>j</sub> = 25 °C	0.45	0.7	-	V
		T <sub>j</sub> = 150 °C	0.25	0.4	-	V
I <sub>DSS</sub>	drain-source leakage current	V <sub>DS</sub> = 20 V; V <sub>GS</sub> = 0 V				
		T <sub>j</sub> = 25 °C	-	-	1	μΑ
		T <sub>j</sub> = 150 °C	-	-	100	μΑ
I <sub>GSS</sub>	gate-source leakage current	$V_{GS} = \pm 8 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nΑ
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 2 \text{ A}; Figure 7 and 8$				
		T <sub>j</sub> = 25 °C	-	30	36	$m\Omega$
		T <sub>j</sub> = 150 °C	-	48	57.6	$m\Omega$
		V <sub>GS</sub> = 2.5 V; I <sub>D</sub> = 1.5 A; Figure 7 and 8	-	36	43	$m\Omega$
		$V_{GS} = 1.8 \text{ V}; I_D = 1 \text{ A}; Figure 7 and 8$	-	44	63	$m\Omega$
Dynamic	characteristics					
Q <sub>g(tot)</sub>	total gate charge	$I_D = 5 \text{ A}$ ; $V_{DD} = 10 \text{ V}$ ; $V_{GS} = 4.5 \text{ V}$ ; Figure 13	-	7.4	-	nC
Q <sub>gs</sub>	gate-source charge		-	1.2	-	nC
$Q_{gd}$	gate-drain (Miller) charge		-	1.8	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 20 \text{ V}; f = 1 \text{ MHz}; Figure 11$	-	460	-	pF
C <sub>oss</sub>	output capacitance		-	100	-	рF
C <sub>rss</sub>	reverse transfer capacitance		-	70	-	рF
t <sub>d(on)</sub>	turn-on delay time	$V_{DD}$ = 10 V; $R_L$ = 10 $\Omega$ ; $V_{GS}$ = 4.5 V; $R_G$ = 6 $\Omega$	-	7	-	ns
t <sub>r</sub>	rise time	_	-	13	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	53	-	ns
t <sub>f</sub>	fall time	_	-	13	-	ns
Source-d	drain diode					
$V_{SD}$	source-drain (diode forward) voltage	I <sub>S</sub> = 1.7 A; V <sub>GS</sub> = 0 V; Figure 12	-	0.81	1.2	V

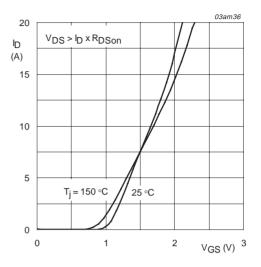
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T<sub>i</sub> = 25 °C

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values.



 $T_{j}$  = 25 °C and 150 °C;  $V_{DS} > I_{D} \times R_{DSon}$ 

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values.

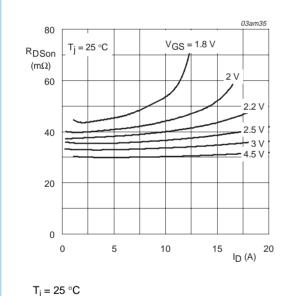
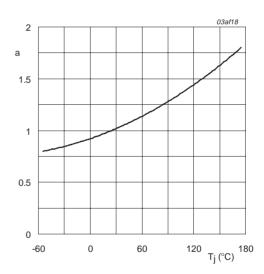


Fig 7. Drain-source on-state resistance as a function

of drain current; typical values.

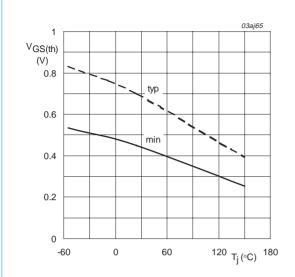


$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 8. Normalized drain source on-state resistance factor as a function of junction temperature.

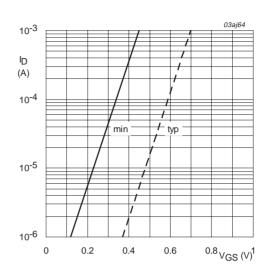


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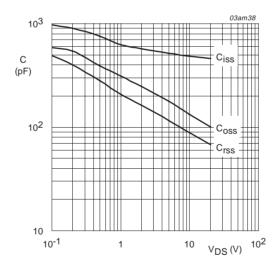
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$ 

Fig 9. Gate-source threshold voltage as a function of junction temperature.



 $T_i = 25 \,^{\circ}C; \, V_{DS} = 5 \,^{\circ}V$ 

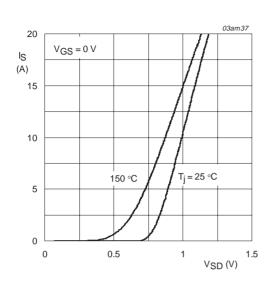
Fig 10. Sub-threshold drain current as a function of gate-source voltage.



 $V_{GS} = 0 V$ ; f = 1 MHz

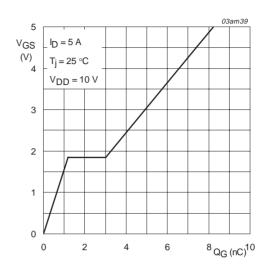
Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

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 $T_i$  = 25 °C and 150 °C;  $V_{GS}$  = 0 V

Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.



 $I_D = 5 A; V_{DD} = 10 V$ 

Fig 13. Gate-source voltage as a function of gate charge; typical values.



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# 6. Package outline

Plastic surface mounted package; 3 leads

SOT23

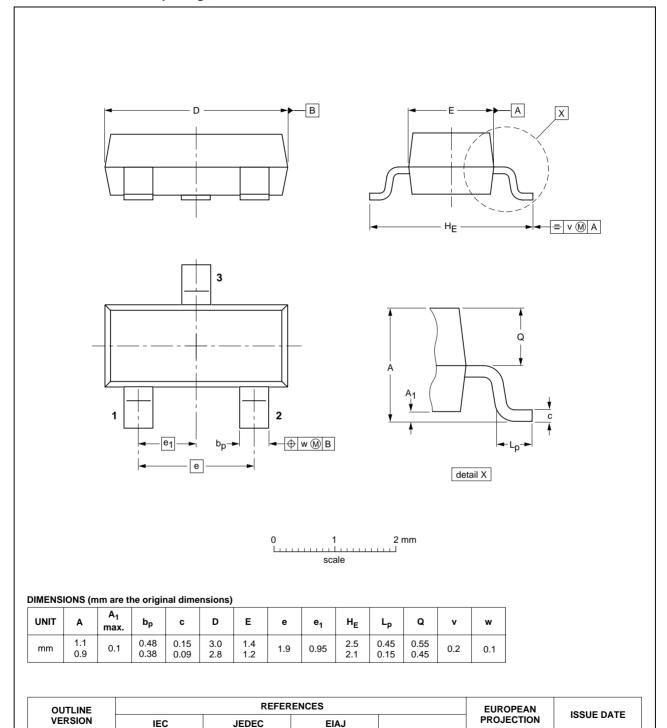


Fig 14. SOT23.

SOT23

 $\square$ 

97-02-28

99-09-13

TO-236AB



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# 7. Revision history

# Table 5: Revision history

Rev	Date	CPCN	Description
01	20030625	-	Product data (9397 750 11569)

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### µTrenchMOS™ ultra low level FET

#### 8. Data sheet status

Level	Data sheet status <sup>[1]</sup>	Product status <sup>[2][3]</sup>	Definition
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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